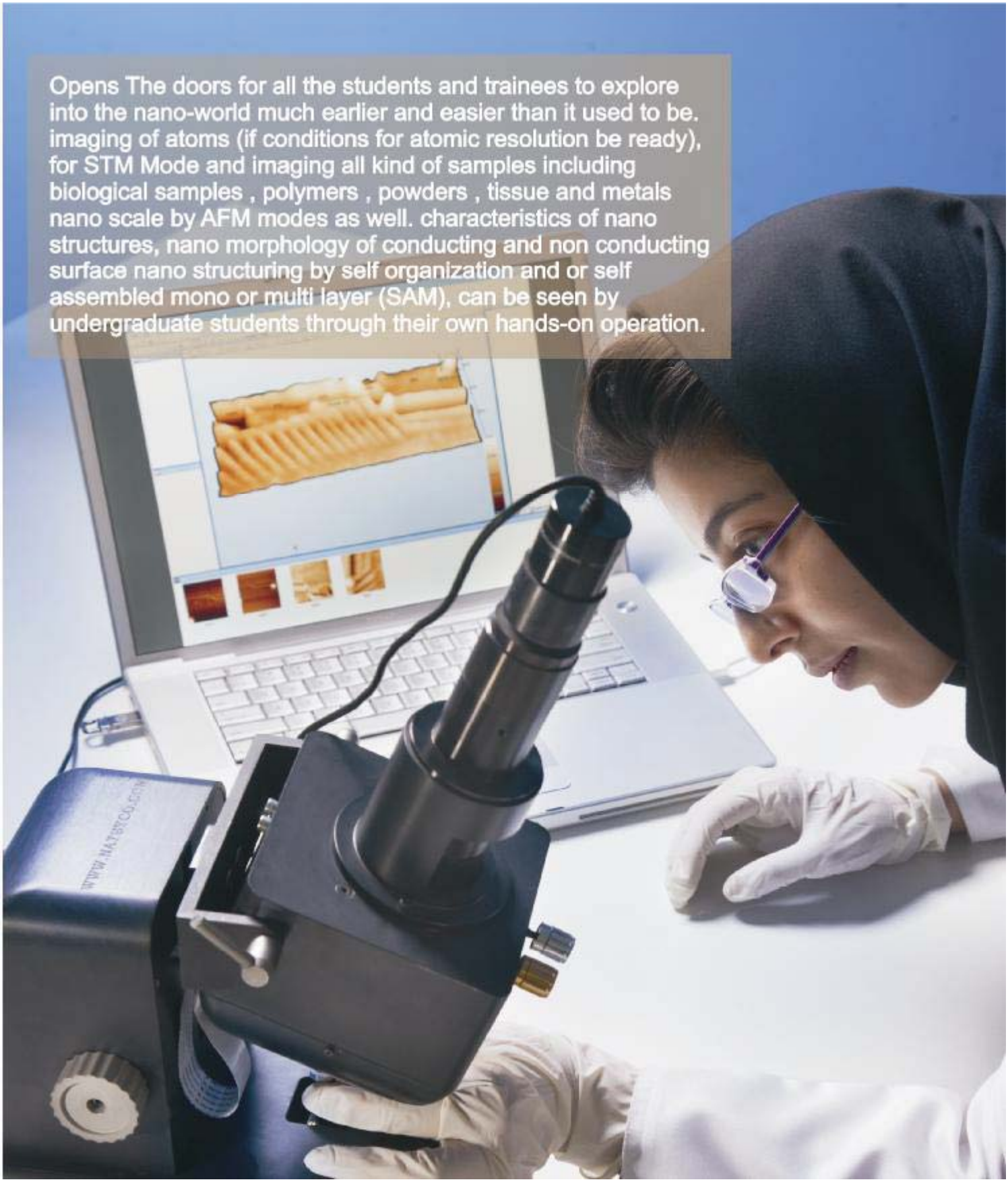
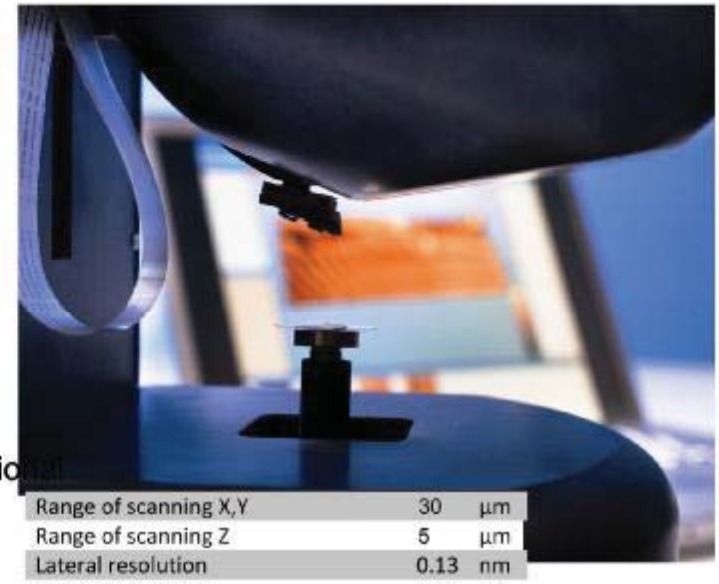
EDUCATIONAL

Scanning Probe Microscope(EDU)



Scanning Probe
MICROSCOPE (EDU)

Featuring aninnovational ergonomic design and improved electronics, this Scientific Microscope delivers atomic-scale resolution at a remarkably affordable price, making it an ideal choice for education as well as research. The NAMA-SPM(EDU) offers educators an exceptional their students to many powerful SPM/AFM-STM techniques.



Range of scanning X,Y	30	µm
Range of scanning Z	5	µm
Lateral resolution	0.13	nm
Vertical resolution	0.05	nm
Scanning schema: Movable sample under stationary probe		
Scanner type: Piezo ceramic		
Maximum sample size	20	mm
XY Micro positioning stage	2.5	µm
Embedded video system: visualization on a PC connector via USB port from top and side.		
Scanner DAC/ADC resolution	16	bit

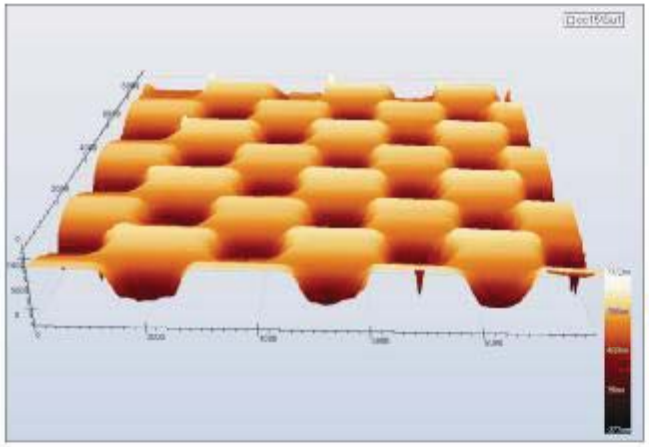
Features

AFM Mode:

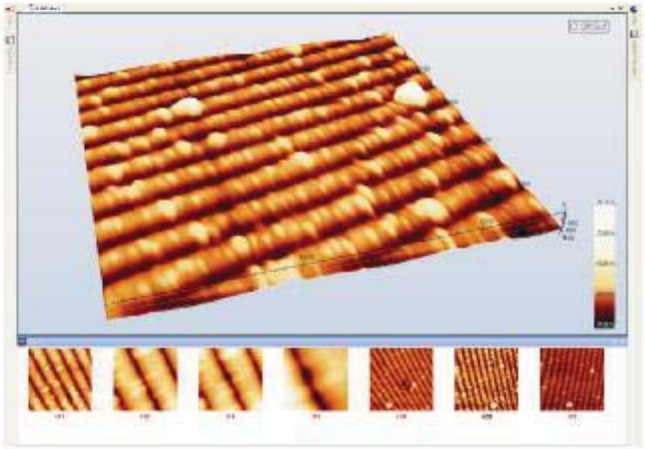
-Contact Mode (Constant Force and Constant Height Available)
- Noncontact Mode
- Semi Contact Mode
- Force Spectroscopy
- LFM (Lateral Force Microscopy)
- MFM (Magnetic Force Microscopy)
- EFM (Electrostatic Force Microscopy)
- PDM (Phases Detection Microscopy)
- FMM (Force Modulation Microscopy)

STM Mode:

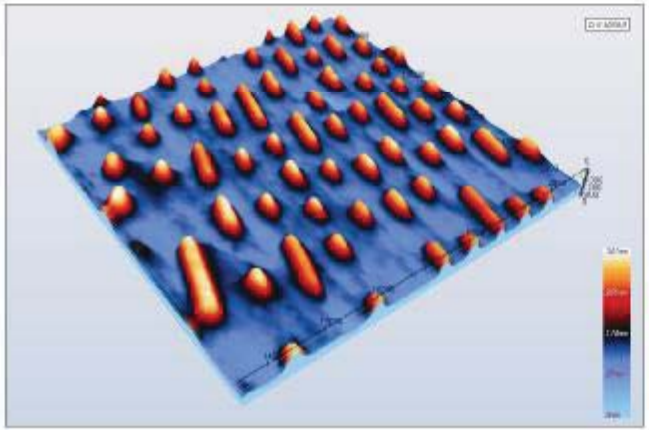
- Constant Height
- Constant Current
- Spectroscopy



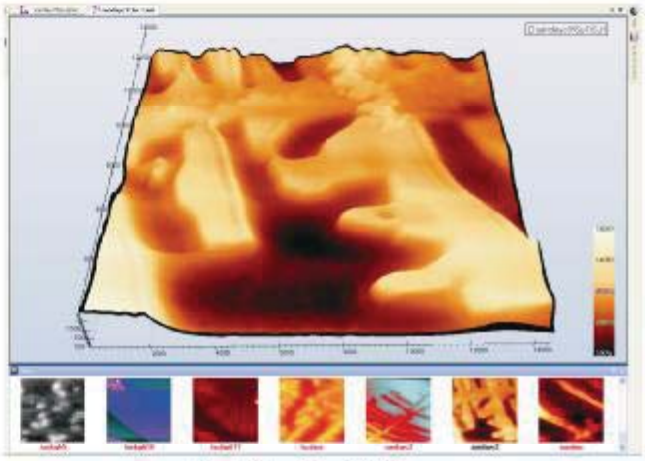
Calibration Sample



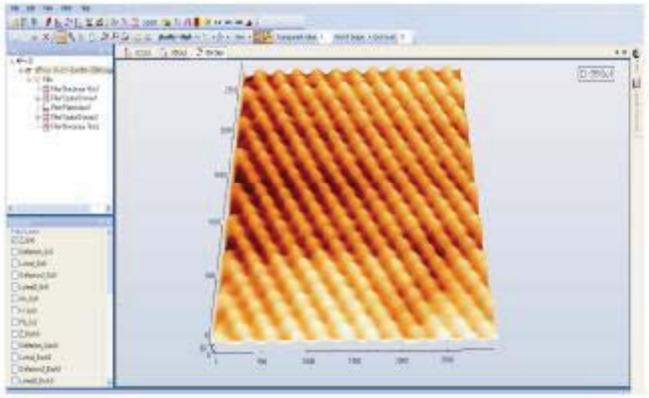
DVD Surface



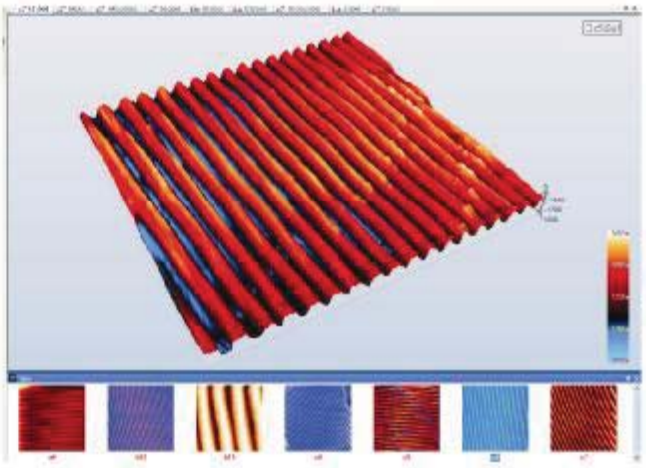
Calibration Sample



Peptide Scaffold



Calibration Sample



Calibration Sample

ISO 9001

UKAS QUALITY MANAGEMENT 043

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